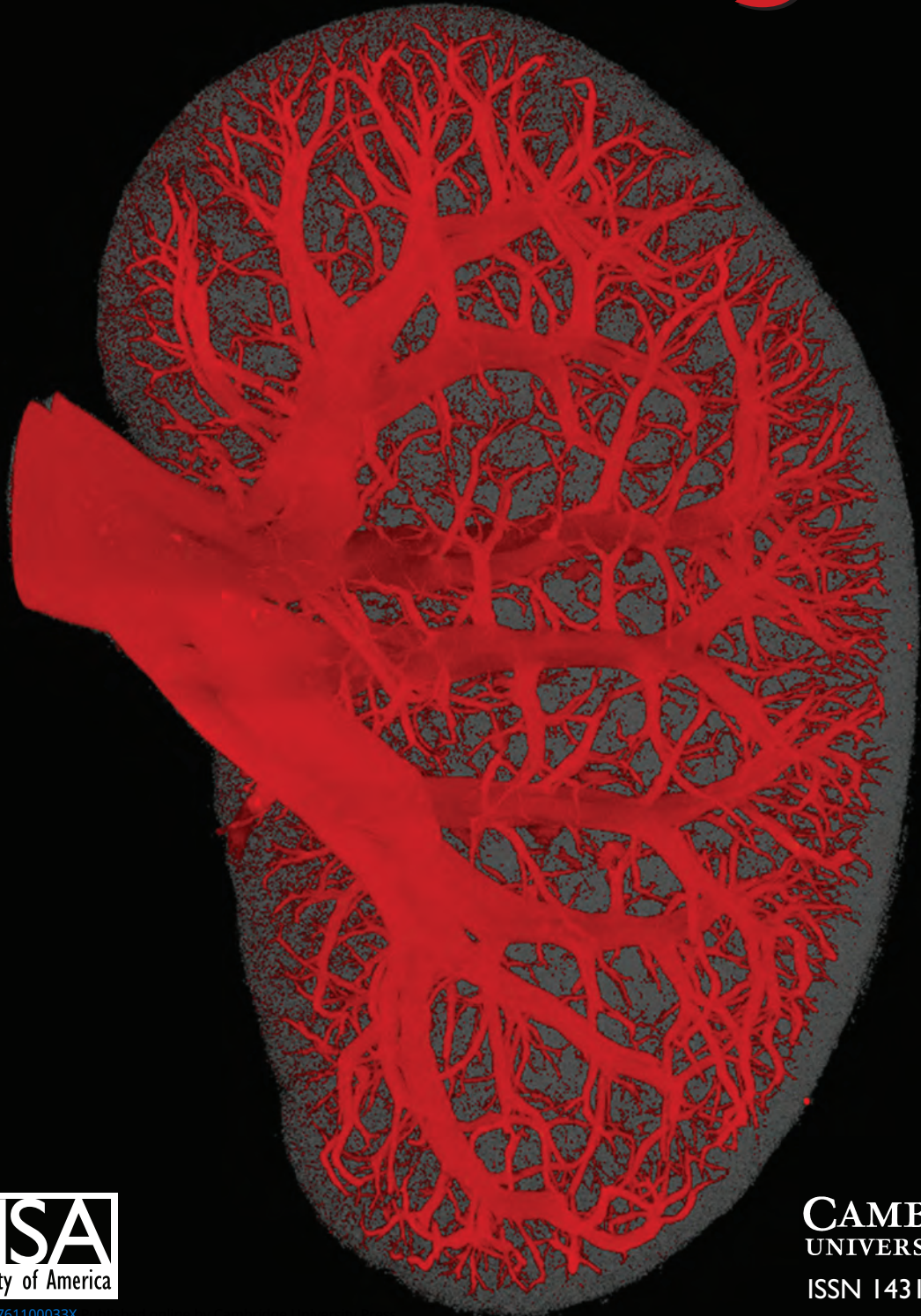


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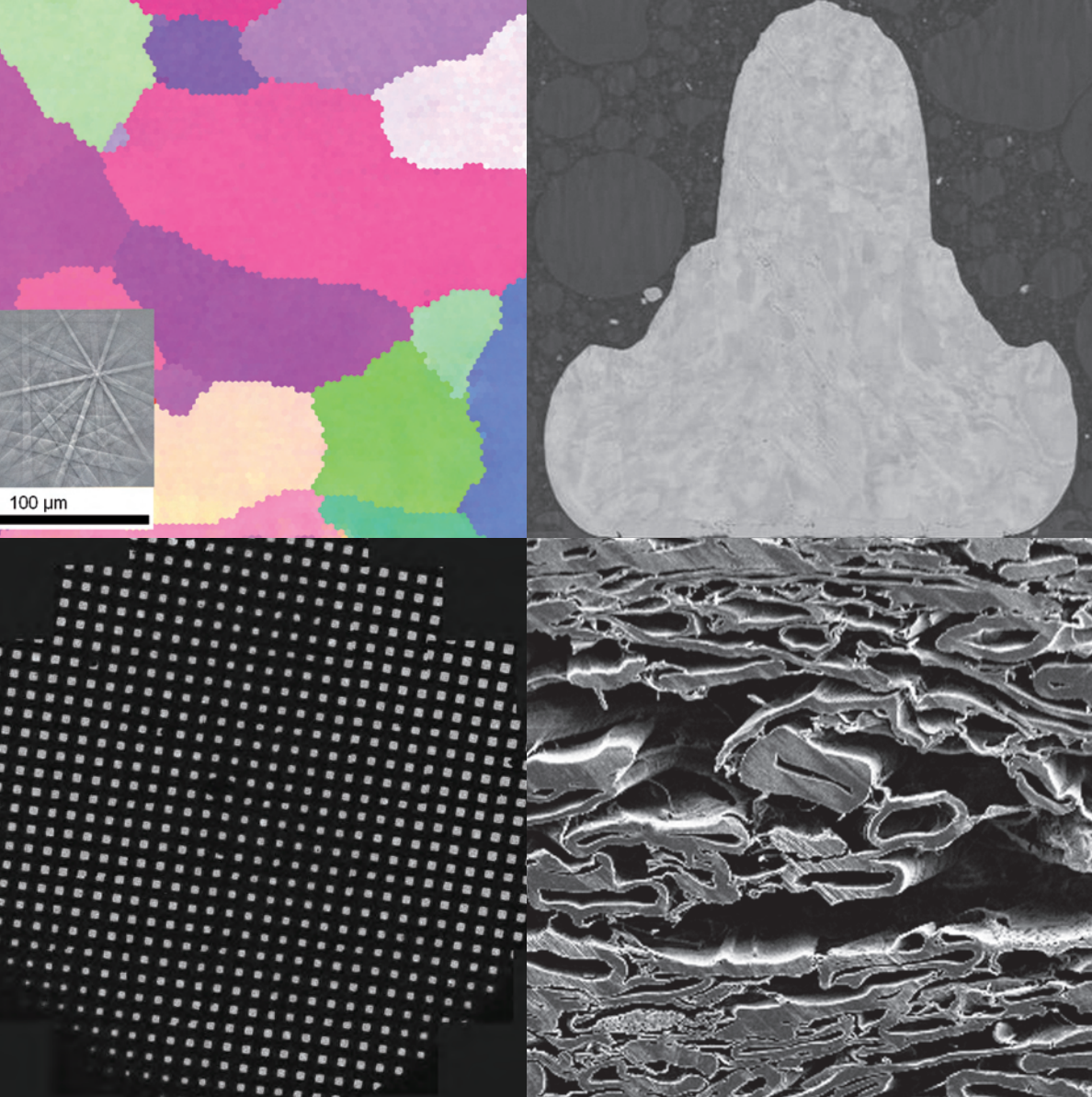
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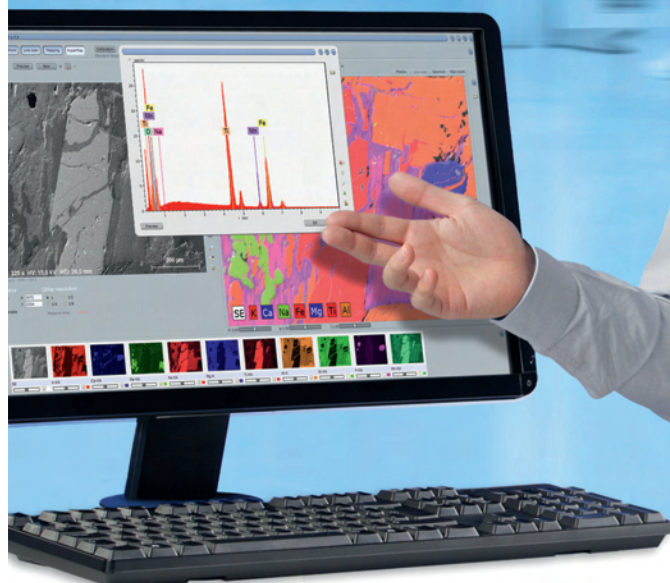
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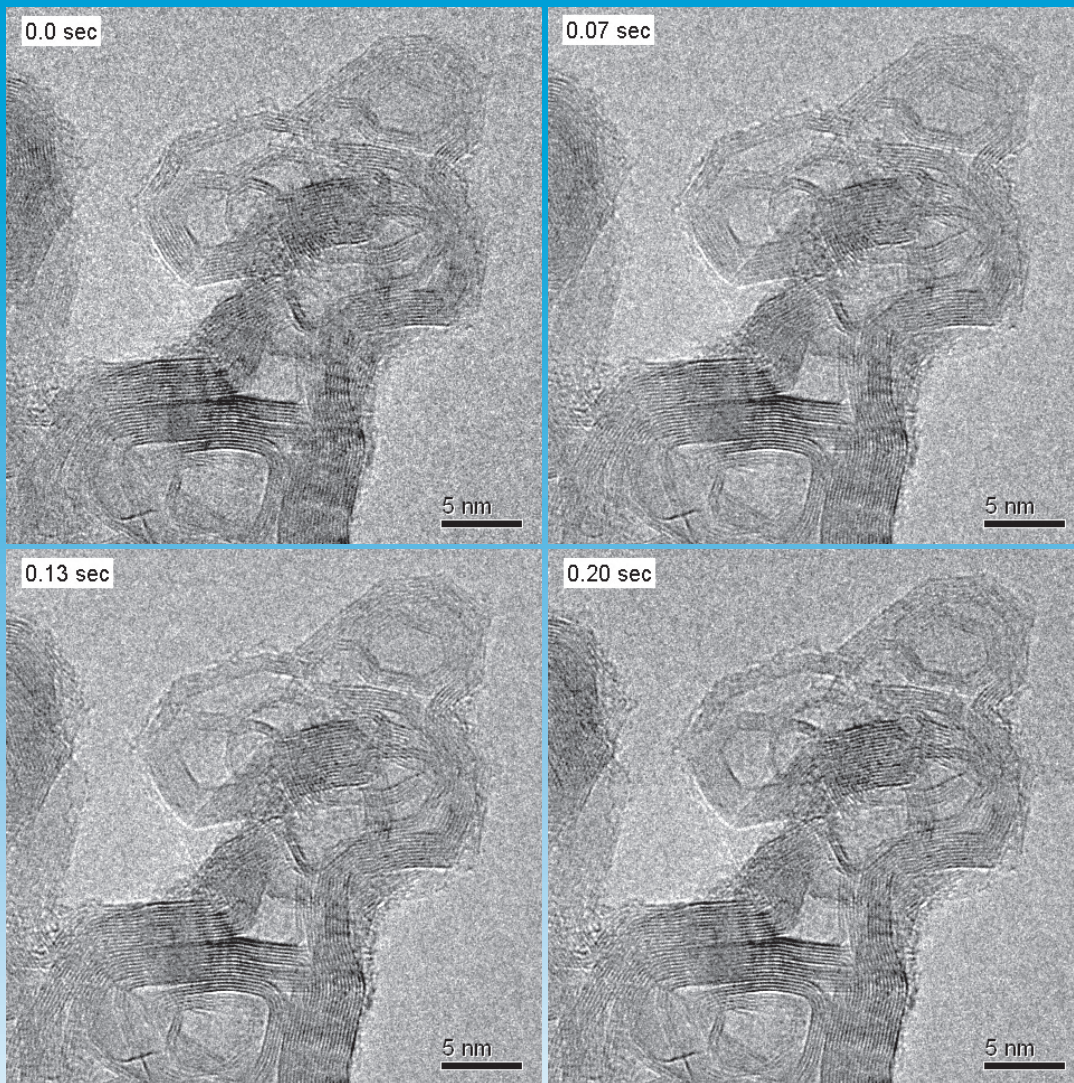


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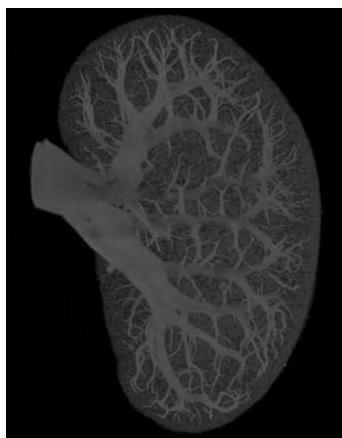
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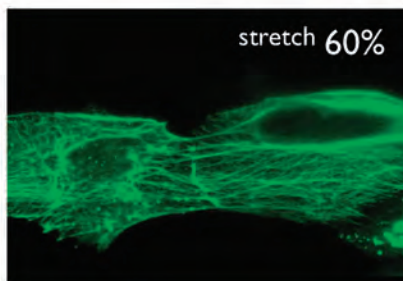
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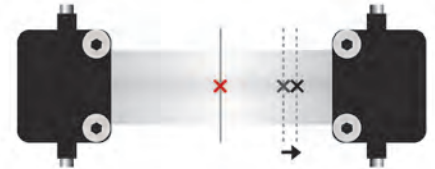
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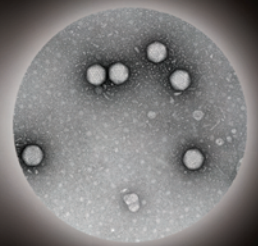
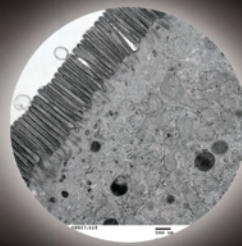
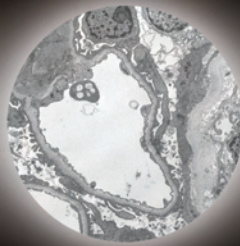
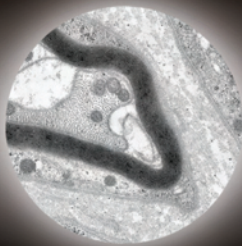
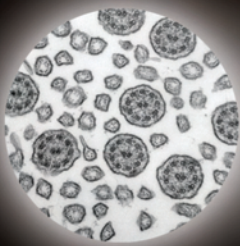


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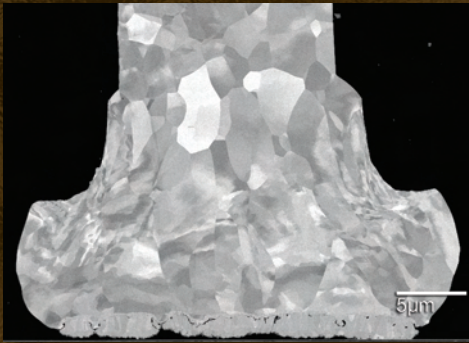
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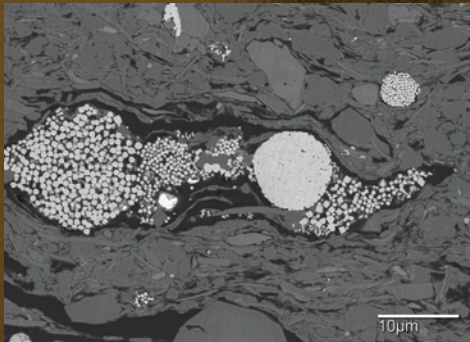
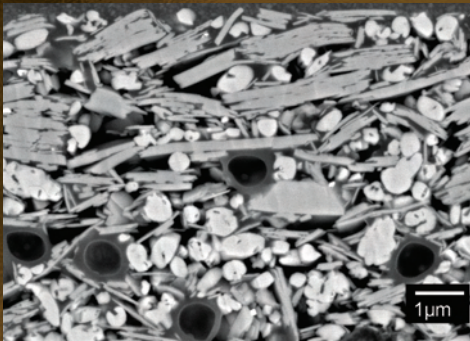
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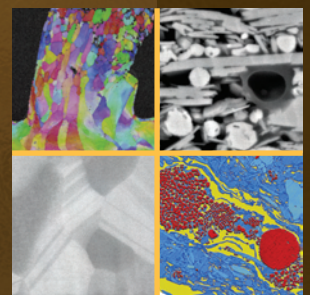
Paper, shale, solar thin films, yeast, latex beads, solder bumps and wire bonds are just a few difficult materials that our customers routinely and pristinely cross section with the **JEOL** ion beam **Cross Section Polisher**.

Send us your most difficult samples and we'll show you how to achieve cross sections without deformation. Need more proof? Visit our extensive gallery of images at www.jeolusa.com/CP2.



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